

Docket No.: 63979-033



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277
Yoshihiko KANZAWA, et al. : Confirmation Number: 5372
Serial No.: 10/674,523 : Group Art Unit: To be Assigned
Filed: October 01, 2003 : Examiner: To be Assigned
For: METHOD FOR MEASURING SEMICONDUCTOR CONSTITUENT ELEMENT
CONTENT AND METHOD FOR MANUFACTURING A SEMICONDUCTOR DEVICE (As
amended)

TRANSMITTAL OF FORMAL DRAWINGS

Mail Stop
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

At the time the above application was filed, informal drawings were presented with the application.

The formal drawings are submitted herewith.

Respectfully submitted,

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Date: May 5, 2004



VERIFICATION OF TRANSLATION

Re: U.S. Patent Application Serial No. 10/674,523

I, Yoshiko TAMURA, of Kitahama TNK Building,
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hereby declare that I am the translator of the
document attached and certify that the following is
true translation to the best of my knowledge and
belief.

Signature of translator

Yoshiko Tamura

Yoshiko TAMURA

Dated this 26th day of March, 2004